

# Search Notes



Application/Control No.

09/829,151

Examiner

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Applicant(s)/Patent under Reexamination

YOUNG, ALAN

Art Unit

3629

## SEARCHED

Class	Subclass	Date	Examiner
705	1	7/9/05	DN
	7		
	8		
	9		
	10		
706	12		
	46		
	52		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I US	7/9/05	DN
1. Patent		
2. PG Pub		
II FOREIGN		
epo		
JPO		
Derwent		
IBM-TDB		